





TPS7B87-Q1 SBVS363A - DECEMBER 2020 - REVISED APRIL 2021

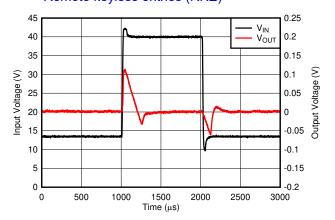
TPS7B87-Q1 500-mA, 40-V, Low-Dropout Regulator With Power-Good

1 Features

- AEC-Q100 qualified for automotive applications:
 - Temperature grade 1: –40°C to +125°C, T_A
 - Junction temperature: –40°C to +150°C, T_J
- Input voltage range: 3 V to 40 V (42 V max)
- Output voltage range: 3.3 V and 5 V (fixed)
- Maximum output current: 500 mA
- Output voltage accuracy: ±0.85% (max)
- Low dropout voltage:
 - 475 mV (max) at 450 mA
- Low quiescent current:
 - 17 μA (typ) at light loads
- Excellent line transient response:
 - ±2% V_{OUT} deviation during cold-crank
 - ±2% V_{OUT} deviation (1-V/μs V_{IN} slew rate)
- Power-good with programmable delay period
- Stable with a 2.2-µF or larger capacitor
- Functional Safety-Capable
 - Documentation available to aid functional safety system design
- Package options:
 - 5-pin TO-252 package: 29.7°C/W R_{θ,IA}
 - 8-pin HSOIC-8 package with thermal pad: 41.8°C/W R_{θ,JA}

2 Applications

- Reconfigurable instrument clusters
- Body control modules (BCM)
- Always-on battery-connected applications:
 - Automotive gateways
 - Remote keyless entries (RKE)



Line Transient Response (3-V/µs V_{IN} Slew Rate)

3 Description

The TPS7B87-Q1 is a low-dropout linear regulator designed to connect to the battery in automotive applications. The device has an input voltage range extending to 40 V, which allows the device to withstand transients (such as load dumps) that are anticipated in automotive systems. With only a 17µA quiescent current at light loads, the device is an optimal solution for powering always-on components such as microcontrollers (MCUs) and controller area network (CAN) transceivers in standby systems.

The device has state-of-the-art transient response that allows the output to quickly react to changes in load or line (for example, during cold-crank conditions). Additionally, the device has a novel architecture that minimizes output overshoot when recovering from dropout. During normal operation, the device has a tight DC accuracy of ±0.85% over line, load, and temperature.

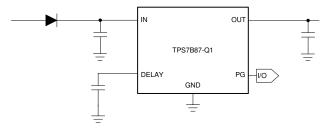
The power-good delay can be adjusted by external components, allowing the delay time to be configured to fit application-specific systems.

The device is available in thermally conductive packaging to allow the device to efficiently transfer heat to the circuit board.

Device Information (1)

| PART NUMBER | PACKAGE | BODY SIZE (NOM) |
|-------------|------------|-------------------|
| TPS7B87-Q1 | HSOIC (8) | 4.89 mm × 3.90 mm |
| | TO-252 (5) | 6.60 mm × 6.10 mm |

For all available packages, see the orderable addendum at the end of the data sheet.



Output Equal to Reference Voltage



Table of Contents

| 1 Features1 | 8 Application and Implementation1 |
|---------------------------------------|--|
| 2 Applications1 | |
| 3 Description1 | |
| 4 Revision History2 | |
| 5 Pin Configuration and Functions3 | |
| 6 Specifications4 | |
| 6.1 Absolute Maximum Ratings4 | |
| 6.2 ESD Ratings 4 | |
| 6.3 Recommended Operating Conditions4 | |
| 6.4 Thermal Information5 | 11.2 Documentation Support2 |
| 6.5 Electrical Characteristics6 | 11.3 Receiving Notification of Documentation Updates 2 |
| 6.6 Switching Characteristics7 | 11.4 Support Resources2 |
| 6.7 Typical Characteristics8 | 11.5 Trademarks2 |
| 7 Detailed Description14 | |
| 7.1 Overview14 | 11.7 Glossary2 |
| 7.2 Functional Block Diagram14 | 12 Mechanical, Packaging, and Orderable |
| 7.3 Feature Description15 | Information2 |
| 7.4 Device Functional Modes17 | |

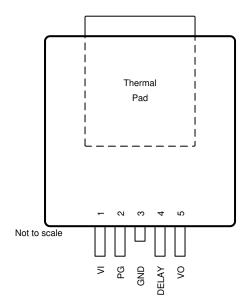
4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

| (| Changes from Revision * (December 2020) to Revision A (April 2021) | Page |
|---|--|------|
| • | Added Functional Safety-Capable bullet to Features list | 1 |
| • | Updated pin functions table to reflect pin 4 of the HSOIC (DDA) package as an NC pin | 3 |



5 Pin Configuration and Functions



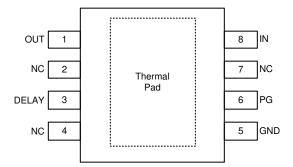


Figure 5-2. DDA Package, 8-Pin HSOIC, Top View

Figure 5-1. KVU Package, 5-Pin TO-252, Top View

Table 5-1. Pin Functions

| | PIN | | TYPE ⁽¹⁾ | DESCRIPTION | |
|-------------|-----|---------|---------------------|---|--|
| NAME | KVU | DDA | ITPE("/ | DESCRIPTION | |
| DELAY | 4 | 3 | I | Power-good delay adjustment pin. Connect a capacitor from this pin to GND to set the PG reset delay. Leave this pin floating for a default (t _(DLY_FIX)) delay. See the <i>Power-Good (PG)</i> section for more information. If this functionality is not desired, leave this pin floating because connecting this pin to GND causes a permanent increase in the GND current. | |
| GND | 3 | 5 | G | Ground reference | |
| NC | _ | 2, 4, 7 | _ | No internal connection. This pin can be left floating or tied to GND for best thermal performance. | |
| PG | 2 | 6 | I | Power-good pin. This pin has an internal pullup resistor. Do not connect this pin to V_{OUT} or any other biased voltage rail. V_{PG} is logic level high when V_{OUT} is above the power-good threshold. See the <i>Power-Good (PG)</i> section for more information. | |
| IN | 1 | 8 | Р | Input power-supply voltage pin. For best transient response and to minimize input impedance, use the recommended value or larger ceramic capacitor from IN to GND as listed in the <i>Recommended Operating Conditions</i> table and the <i>Input Capacitor</i> section. Place the input capacitor as close to the input of the device as possible. | |
| OUT | 5 | 1 | 0 | Regulated output voltage pin. A capacitor is required from OUT to GND for stability. For best transient response, use the nominal recommended value or larger ceramic capacitor from OUT to GND; see the <i>Recommended Operating Conditions</i> table and the <i>Output Capacitor</i> section. Place the output capacitor as close to output of the device as possible. If using a high equivalent series resistance (ESR) capacitor, decouple the output with a 100-nF ceramic capacitor. | |
| Thermal pad | Pad | Pad | _ | Connect the thermal pad to a large area GND plane for improved thermal performance. | |

(1) I = input; O = output; P = power; G = ground.



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

| | | MIN | MAX | UNIT |
|------------------|--|------|------------------------|------|
| V _{IN} | Unregulated input | -0.3 | 42 | V |
| V _{OUT} | Regulated output | -0.3 | $V_{IN} + 0.3 V^{(2)}$ | V |
| Delay | Reset delay input, power-good adjustable threshold | -0.3 | 6 | V |
| PG | Power-good outupt | -0.3 | 20 | V |
| TJ | Operating junction temperature | -40 | 150 | °C |
| T _{stg} | Storage temperature | -65 | 150 | °C |

⁽¹⁾ Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect devicereliability.

6.2 ESD Ratings

| | | | | VALUE | UNIT |
|--------------------|-------------------------|---------------------------------------|--------------------|-------|------|
| | | Human-body model (HBM), per AEC Q100- | 002 ⁽¹⁾ | ±2000 | |
| V _(ESD) | Electrostatic discharge | Charged-device model (CDM), per AEC | All pins | ±500 | V |
| | | Q100-011 | Corner pins | ±750 | |

⁽¹⁾ AEC Q100-002 indicates that HBM stressing shall be in accordancewith the ANSI/ESDA/JEDEC JS-001 specification.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

| | | MIN | TYP | MAX | UNIT |
|--------------------|--|-------|-----|-----|------|
| V _{IN} | Input voltage | 3 | | 40 | V |
| V _{OUT} | Output voltage | 1.2 | | 18 | V |
| I _{OUT} | Output current | 0 | | 500 | mA |
| V _{Delay} | Delay pin voltage, power-good adjustable threshold | 0 | | 5.5 | V |
| V_{PG} | Power-good outupt pin | 0 | | 18 | V |
| C _{OUT} | Output capacitor ⁽²⁾ | 2.2 | | 220 | μF |
| ESR | Output capacitor ESR requirements | 0.001 | | 2 | Ω |
| C _{IN} | Input capacitor ⁽¹⁾ | 0.1 | 1 | | μF |
| C _{Delay} | Power-good delay capacitor | | | 1 | μF |
| TJ | Operating junction temperature | -40 | | 150 | °C |

⁽¹⁾ For robust EMI performance the minimum input capacitance is 500 nF.

(2) Effective output capacitance of 1 µF minimum required for stability.

Submit Document Feedback

Copyright © 2021 Texas Instruments Incorporated

⁽²⁾ The absolute maximum rating is VIN + 0.3 V or 20 V, whichever is smaller



6.4 Thermal Information

| | | | TPS7B87-Q1 | | |
|-----------------------|--|--------|------------|------|--|
| | THERMAL METRIC ⁽¹⁾ (2) | KVU | DDA | UNIT | |
| | | 5 PINS | 8 PINS | | |
| $R_{\theta JA}$ | Junction-to-ambient thermal resistance | 29.7 | 41.8 | °C/W | |
| R _{0JC(top)} | Junction-to-case (top) thermal resistance | 40.2 | 55 | °C/W | |
| $R_{\theta JB}$ | Junction-to-board thermal resistance | 8.6 | 17.3 | °C/W | |
| ΨЈТ | Junction-to-top characterization parameter | 2.9 | 4.5 | °C/W | |
| ΨЈВ | Junction-to-board characterization parameter | 8.5 | 17.3 | °C/W | |
| R _{0JC(bot)} | Junction-to-case (bottom) thermal resistance | 1.5 | 5.7 | °C/W | |

⁽¹⁾ The thermal data is based on the JEDEC standard high K profile, JESD 51-7. Two-signal, two-plane, four-layer board with 2-oz. copper. The copper pad is soldered to the thermal land pattern. Also, correct attachment procedure must be incorporated.

⁽²⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC PackageThermal Metrics application report.



6.5 Electrical Characteristics

specified at T $_J$ = -40°C to +150°C, V $_{IN}$ = 13.5 V, I $_{OUT}$ = 0 mA, C $_{OUT}$ = 2.2 μ F, 1 m Ω < C $_{OUT}$ ESR < 2 Ω , C $_{IN}$ = 1 μ F typical values are at T $_J$ = 25°C

| | PARAMETER | Test Co | onditions | MIN | TYP | MAX | UNIT |
|-------------------------------|--|--|--|-------|------|-------|-------------------|
| | | $V_{IN} = V_{OUT} + 1 \text{ V to } 40 \text{ V, } I_{C}$ 25°C ⁽¹⁾ | $_{DUT}$ = 100 μ A to 450 mA, T _J = | -0.85 | | 0.85 | |
| V _{OUT} | Regulated output | $V_{IN} = V_{OUT} + 1 \text{ V to } 40 \text{ V, } I_{OUT} = 100 \mu\text{A to } 500 \text{ mA, } T_J = 25^{\circ}\text{C}^{(1)}$ | | -0.85 | | 0.85 | % |
| | | $V_{IN} = V_{OUT} + 1 \text{ V to } 40 \text{ V, } I_{C}$ | _{DUT} = 100 μA to 450 mA ⁽¹⁾ | -1.15 | | 1.15 | |
| | | $V_{IN} = V_{OUT} + 1 \text{ V to } 40 \text{ V, } I_{C}$ | _{DUT} = 100 μA to 500 mA ⁽¹⁾ | -1.15 | | 1.15 | |
| $\Delta V_{OUT(\Delta IOUT)}$ | Load regulation | V _{IN} = V _{OUT} + 1 V, I _{OUT} = 10 V | 0 μA to 450 mA , $V_{OUT} \ge 3.3$ | | | 0.425 | % |
| ΔVOUT(ΔΙΟΌΤ) | Load regulation | V _{IN} = V _{OUT} + 1 V, I _{OUT} = 10 V | 0 μA to 500 mA , $V_{OUT} \ge 3.3$ | | | 0.45 | 70 |
| $\Delta V_{OUT(\Delta VIN)}$ | Line regulation | $V_{IN} = V_{OUT} + 1 V \text{ to } 40 V, I_{OUT}$ | _{OUT} = 100 μA | | | 0.2 | % |
| ΔV _{OUT} | Load transient response settling time | $t_R = t_F = 1 \mu s; C_{OUT} = 10 \mu I$ | -, V _{OUT} ≥ 3.3V | | | 100 | μs |
| | | | I _{OUT} = 150 mA to 350 mA | -2% | | | |
| ΔV_{OUT} | Load transient response overshoot, undershoot ⁽²⁾ | t _R = t _F = 1 μs; C _{OUT} = 10 μF | I _{OUT} = 350 mA to 150 mA | | | 10% | %V _{OUT} |
| | | | I _{OUT} = 0 mA to 500 mA | -10% | | | |
| | | $V_{IN} = V_{OUT} + 1 \text{ V to 40V, I}_{O}$ | _{UT} = 0 mA, T _J = 25°C ⁽³⁾ | | 17 | 21 | |
| I_Q | Quiescent current | $V_{IN} = V_{OUT} + 1 \text{ V to } 40 \text{ V, } I_{C}$ | _{DUT} = 0 mA ⁽³⁾ | | | 26 | μΑ |
| | | Ι _{ΟUT} = 500 μΑ | | | | 35 | |
| | | $I_{OUT} \le 1 \text{ mA}, V_{OUT} \ge 3.3 \text{ V}, V_{IN} = V_{OUT(NOM)} \times 0.95$ | | | | 43 | |
| ., | Dropout voltage fixed output | I_{OUT} = 315 mA, $V_{OUT} \ge 3.3$ V, $V_{IN} = V_{OUT(NOM)}$ | | | 260 | 360 | |
| V_{DO} | voltages (DDA Package) | I_{OUT} = 450 mA, $V_{OUT} \ge 3.3$ V, $V_{IN} = V_{OUT(NOM)}$ | | | 335 | 475 | mV |
| | | $I_{OUT} = 500 \text{ mA}, V_{OUT} \ge 3.3 \text{ V}, V_{IN} = V_{OUT(NOM)}$ | | | 360 | 535 | |
| | | $I_{OUT} \le 1 \text{ mA}, V_{OUT} \ge 3.3 \text{ V}, V_{IN} = V_{OUT(NOM)} \times 0.95$ | | | | 46 | |
| V | Dropout voltage fixed output | I _{OUT} = 315 mA, V _{OUT} ≥ 3.3 | V, V _{IN} = V _{OUT(NOM)} | | 275 | 400 | m\/ |
| V_{DO} | voltages (KVU Package) | I _{OUT} = 450 mA, V _{OUT} ≥ 3.3 V, V _{IN} = V _{OUT(NOM)} | | | 360 | 525 | - mV |
| | | I _{OUT} = 500 mA, V _{OUT} ≥ 3.3 V, V _{IN} = V _{OUT(NOM)} | | | 390 | 575 | |
| V _{UVLO(RISING)} | Rising input supply UVLO | V _{IN} rising | | 2.6 | 2.7 | 2.82 | V |
| V _{UVLO(FALLING)} | Falling input supply UVLO | V _{IN} falling | | 2.38 | 2.5 | 2.6 | V |
| V _{UVLO(HYST)} | V _{UVLO(IN)} hysteresis | | | | 230 | | mV |
| I _{CL} | Output current limit | V _{IN} = V _{OUT} + 1 V, V _{OUT} sho | rt to 90% x V _{OUT(NOM)} | 540 | | 780 | mA |
| PSRR | Power supply rejection ratio | V _{IN} - V _{OUT} = 1 V, frequency | = 1 kHz, I _{OUT} = 450 mA | | 70 | | dB |
| R _{PG} | Power-good internal pull up resistor | | | 10 | 30 | 50 | kΩ |
| V _{PG(OL)} | PG pin low level output voltage | V _{OUT} ≤ 0.83 x V _{OUT} | | | | 0.4 | V |
| V _{PG(TH,RISING)} | Default power-good threshold | V _{OUT} rising | | 85 | | 95 | |
| V _{PG(TH,FALLING)} | Default power-good threshold | V _{OUT} falling | | 83 | | 93 | %V _{OUT} |
| V _{PG(HYST)} | Power-good hysteresis | | | | 2 | | |
| $V_{DLY(TH)}$ | Threshold to release power- good high | Voltage at DELAY pin rising | | 1.17 | 1.21 | 1.25 | V |
| I _{DLY(CHARGE)} | Delay capacitor charging current | Voltage at DELAY pin = 1 V | | 1 | 1.5 | 2 | μΑ |
| T _J | Junction temperature | | | -40 | | 150 | °C |
| T _{SD(SHUTDOWN)} | Junction shutdown temperature | | | | 175 | | °C |

6.5 Electrical Characteristics (continued)

specified at T_J = -40°C to +150°C, V_{IN} = 13.5 V, I_{OUT} = 0 mA, C_{OUT} = 2.2 μ F, 1 m Ω < C_{OUT} ESR < 2 Ω , C_{IN} = 1 μ F typical values are at T_J = 25°C

| | PARAMETER | Test Conditions | MIN | TYP | MAX | UNIT |
|-----------------------|--------------------------------|-----------------|-----|-----|-----|------|
| T _{SD(HYST)} | Hysteresis of thermal shutdown | | | 20 | | °C |

- (1) Power dissipation is limited to 2 W for device production testing purposes. The power dissipation can be higher during normal operation. See the thermal dissipation section for more information on how much power the device can dissipate while maintaining a junction temperature below 150°C.
- (2) Specified by design.
- (3) For the adjustable output this is tested in unity gain and resistor current is not included.

6.6 Switching Characteristics

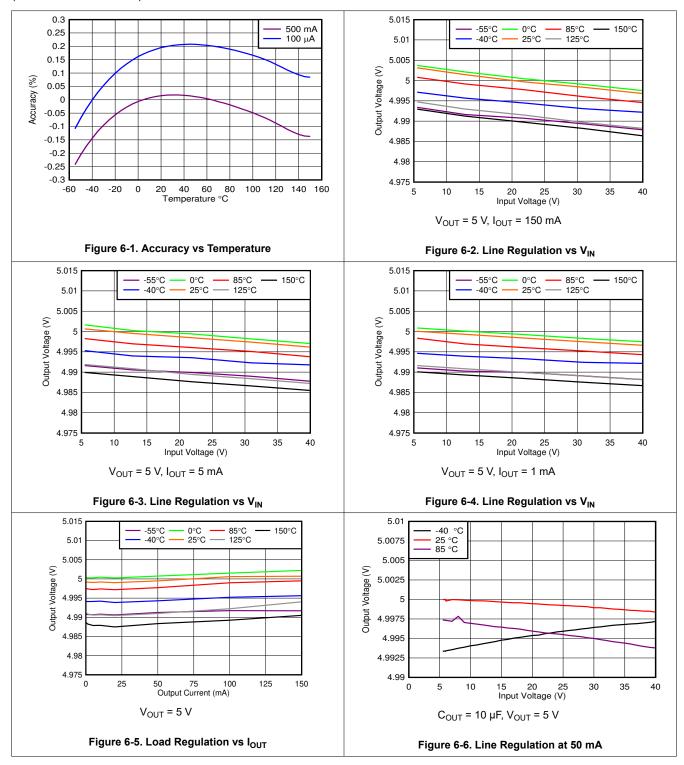
over operating free-air temperature range (unless otherwise noted)

| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|-------------------------|------------------------------|---|-----|-----|-----|------|
| TIMING POV | TIMING POWER-GOOD | | | | | |
| t _(DLY_FIX) | Power-good propagation delay | No capacitor connect at DELAY pin | | 100 | | μs |
| t _(Deglitch) | Power-good deglitch time | No capacitor connect at DELAY pin | | 90 | | μs |
| t _(DLY) | Power-good propagation delay | Delay capacitor value: C _(DELAY) = 100 nF | | 80 | | ms |



6.7 Typical Characteristics

specified at T_J = -40°C to +150°C, V_{IN} = 13.5 V, I_{OUT} = 100 μ A, C_{OUT} = 2.2 μ F, 1 m Ω < C_{OUT} ESR < 2 Ω , and C_{IN} = 1 μ F (unless otherwise noted)



specified at T_J = -40° C to +150°C, V_{IN} = 13.5 V, I_{OUT} = 100 μ A, C_{OUT} = 2.2 μ F, 1 m Ω < C_{OUT} ESR < 2 Ω , and C_{IN} = 1 μ F (unless otherwise noted)

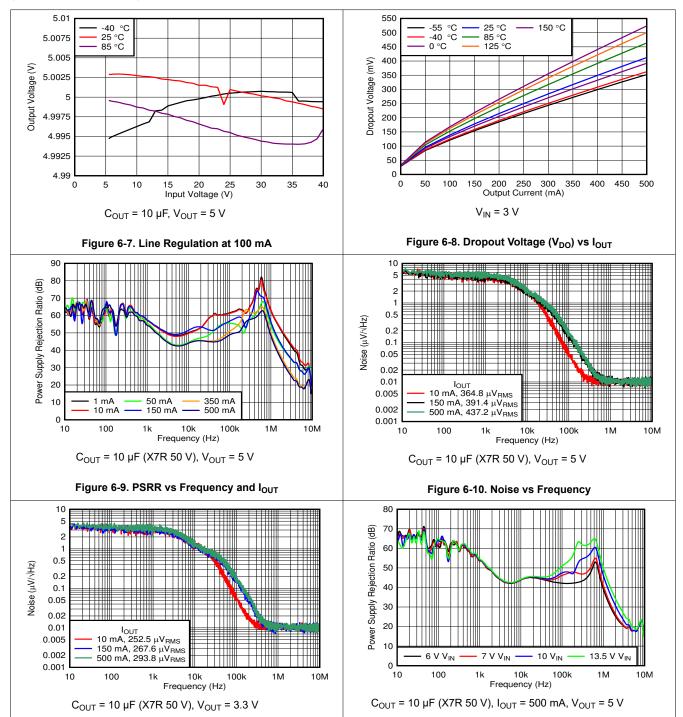
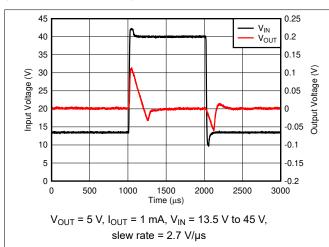


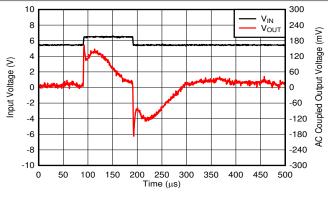
Figure 6-11. Noise vs Frequency

Figure 6-12. PSRR vs Frequency and VIN



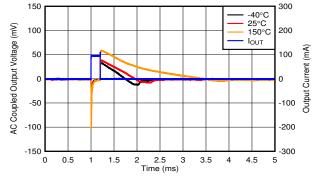
specified at T_J = -40° C to +150°C, V_{IN} = 13.5 V, I_{OUT} = 100 μ A, C_{OUT} = 2.2 μ F, 1 m Ω < C_{OUT} ESR < 2 Ω , and C_{IN} = 1 μ F (unless otherwise noted)





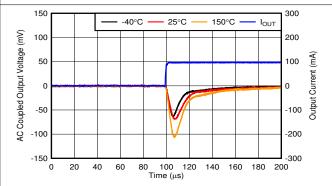
 V_{OUT} = 5 V, I_{OUT} = 100 mA, V_{IN} = 5.5 V to 6.5 V, $rise\ time = 1\ \mu s$

Figure 6-13. Line Transients



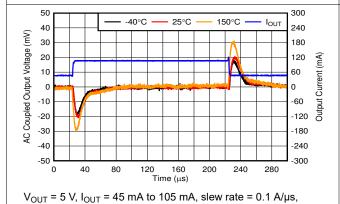
 V_{OUT} = 5 V, I_{OUT} = 0 mA to 100 mA, slew rate = 1 A/µs, C_{OUT} = 10 μF

Figure 6-14. Line Transients



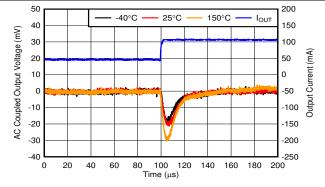
 V_{OUT} = 5 V, I_{OUT} = 0 mA to 100 mA, slew rate = 1 A/µs, C_{OUT} = 10 µF

Figure 6-15. Load Transient, No Load to 100 mA



 C_{OUT} = 10 μF Figure 6-17. Load Transient, 45 mA to 105 mA

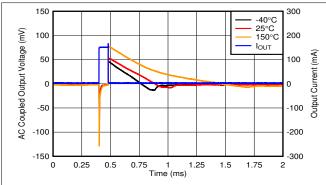




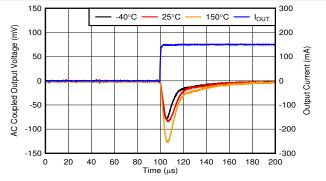
 V_{OUT} = 5 V, I_{OUT} = 45 mA to 105 mA, slew rate = 0.1 A/µs, C_{OUT} = 10 µF

Figure 6-18. Load Transient, 45-mA to 105-mA Rising Edge

specified at T_J = -40°C to +150°C, V_{IN} = 13.5 V, I_{OUT} = 100 μ A, C_{OUT} = 2.2 μ F, 1 m Ω < C_{OUT} ESR < 2 Ω , and C_{IN} = 1 μ F (unless otherwise noted)

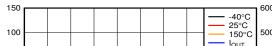


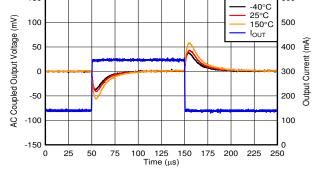
 $V_{OUT} = 5 \text{ V}$, $I_{OUT} = 0 \text{ mA}$ to 150 mA, slew rate = 1 A/ μ s, $C_{OUT} = 10 \mu F$



 $V_{OUT} = 5 \text{ V}$, $I_{OUT} = 0 \text{ mA}$ to 150 mA, slew rate = 1 A/ μ s, C_{OUT} = 10 μF

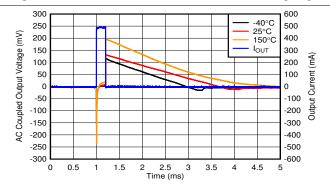
Figure 6-19. Load Transient, No Load to 150-mA





 V_{OUT} = 5 V, I_{OUT} = 150 mA to 350 mA, slew rate = 0.1 A/µs, $C_{OUT} = 10 \mu F$

Figure 6-20. Load Transient, No Load to 150-mA Rising Edge



 V_{OUT} = 5 V, I_{OUT} = 0 mA to 500 mA, slew rate = 1 A/µs, $C_{OUT} = 10 \mu F$

Figure 6-21. Load Transient, 150-mA to 350-mA

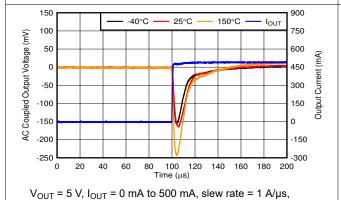
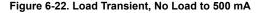
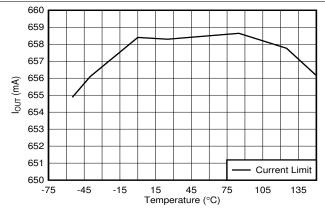


Figure 6-23. Load Transient, No Load to 500-mA Rising Edge

 $C_{OUT} = 10 \mu F$





 $V_{IN} = V_{OUT} + 1 V$, $V_{OUT} = 90\% \times V_{OUT(NOM)}$

Figure 6-24. Output Current Limit vs Temperature



specified at T_J = -40° C to +150°C, V_{IN} = 13.5 V, I_{OUT} = 100 μ A, C_{OUT} = 2.2 μ F, 1 m Ω < C_{OUT} ESR < 2 Ω , and C_{IN} = 1 μ F (unless otherwise noted)

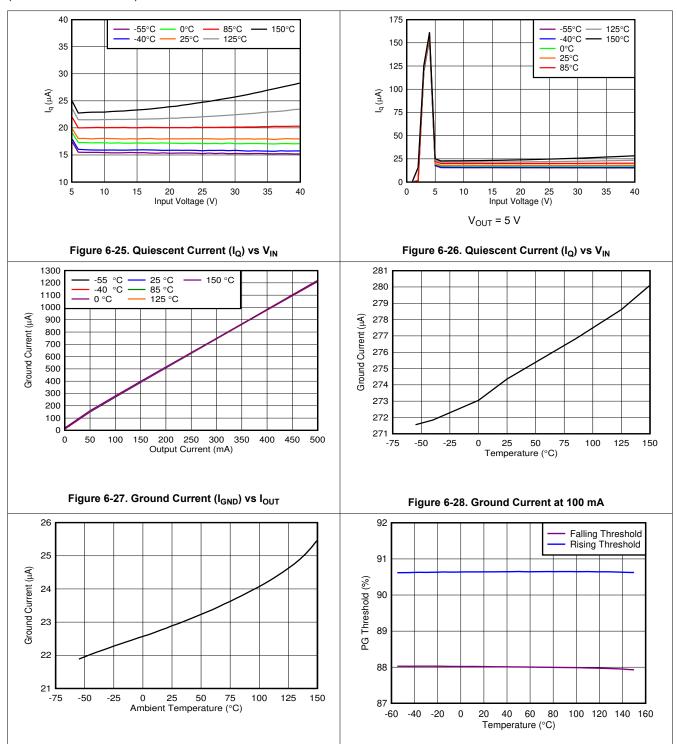
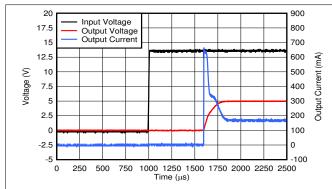


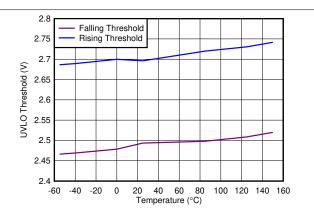
Figure 6-29. Ground Current at 500 µA

Figure 6-30. PG Threshold vs Temperature

specified at T_J = -40°C to +150°C, V_{IN} = 13.5 V, I_{OUT} = 100 μ A, C_{OUT} = 2.2 μ F, 1 m Ω < C_{OUT} ESR < 2 Ω , and C_{IN} = 1 μ F (unless otherwise noted)



 V_{IN} = 13.5 V, V_{OUT} = 5 V, I_{OUT} = 150 mA, C_{OUT} = 10 μF



Temperature

Figure 6-32. Undervoltage Lockout (UVLO) Threshold vs

Figure 6-31. Startup Plot Inrush Current

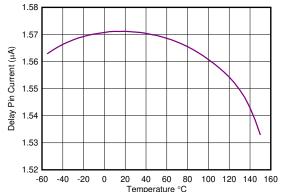
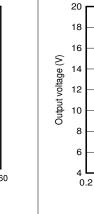


Figure 6-33. Delay Pin Current vs Temperature

 $V_{DELAY} = 1 V$



0.4

0.6

Figure 6-34. Output Voltage vs Injected Current

Injected current (mA)

1.2

1.4

1.6

1.8

8.0

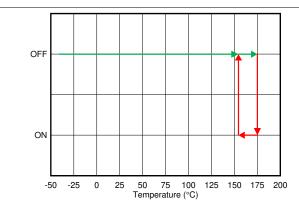


Figure 6-35. Thermal Shutdown

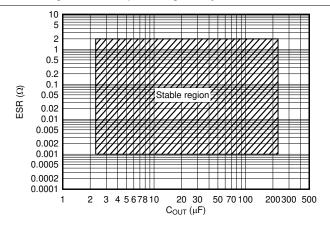


Figure 6-36. Stability, ESR vs C_{OUT}



7 Detailed Description

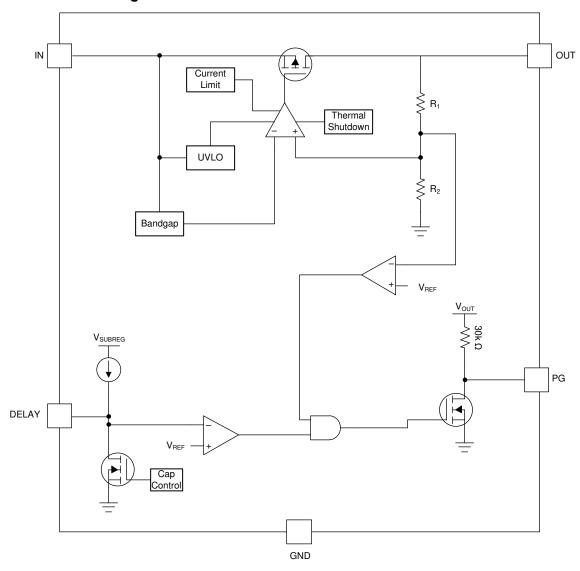
7.1 Overview

The TPS7B87-Q1 is a low-dropout linear regulator (LDO) with improved transient performance that allows for quick response to changes in line or load conditions. The device aslo features a novel output overshoot reduction feature that minimizes output overshoot during cold-crank conditions.

The integrated power-good and delay features allow for the system to notify down-stream components when the power is good and assist in sequencing requirements.

During normal operation, the device has a tight DC accuracy of ±0.85% over line, load, and temperature. The increased accuracy allows for the powering of sensitive analog loads or sensors.

7.2 Functional Block Diagram



Submit Document Feedback

Copyright © 2021 Texas Instruments Incorporated

7.3 Feature Description

7.3.1 Power-Good (PG)

The PG signal provides an easy solution to meet demanding sequencing requirements because PG alerts when the output nears its nominal value. PG can be used to signal other devices in a system when the output voltage is near, at, or above the set output voltage (V_{OUT(nom)}). Figure 7-1 shows a simplified schematic. The PG signal is an internal pullup resistor to the nominal output voltage and is active high. The PG circuit sets the PG pin into a high-impedance state to indicate that the power is good.

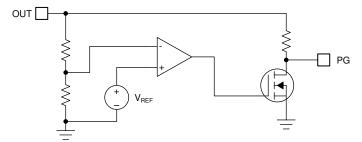
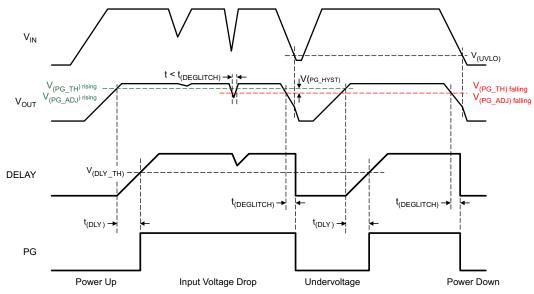


Figure 7-1. Simplified Power-Good Schematic

7.3.2 Adjustable Power-Good Delay Timer (DELAY)

The power-good delay period is a function of the external capacitor on the DELAY pin. The adjustable delay configures the amount of time required before the PG pin becomes high. This delay is configured by connecting an external capacitor from this pin to GND. Figure 7-2 shows the typical timing diagram for the power-good delay pin. If the DELAY pin is left floating, the power-good delay is $t_{(DLY_FIX)}$. For more information on how to program the PG delay, see the *Setting the Adjustable Power-Good Delay* section.



 $V_{(PG\ TH)\ falling} = V_{(PG\ TH)\ rising} - V_{(PG\ HYST)}$

Figure 7-2. Typical Power-Good Timing Diagram

7.3.3 Undervoltage Lockout

The device has an independent undervoltage lockout (UVLO) circuit that monitors the input voltage, allowing a controlled and consistent turn on and off of the output voltage. To prevent the device from turning off if the input drops during turn on, the UVLO has hysteresis as specified in the *Electrical Characteristics* table.

7.3.4 Thermal Shutdown

The device contains a thermal shutdown protection circuit to disable the device when the junction temperature (T_J) of the pass transistor rises to $T_{SD(shutdown)}$ (typical). Thermal shutdown hysteresis assures that the device resets (turns on) when the temperature falls to $T_{SD(reset)}$ (typical).

The thermal time-constant of the semiconductor die is fairly short, thus the device may cycle on and off when thermal shutdown is reached until power dissipation is reduced. Power dissipation during startup can be high from large $V_{\text{IN}} - V_{\text{OUT}}$ voltage drops across the device or from high inrush currents charging large output capacitors. Under some conditions, the thermal shutdown protection disables the device before startup completes.

For reliable operation, limit the junction temperature to the maximum listed in the *Recommended Operating Conditions* table. Operation above this maximum temperature causes the device to exceed its operational specifications. Although the internal protection circuitry of the device is designed to protect against thermal overall conditions, this circuitry is not intended to replace proper heat sinking. Continuously running the device into thermal shutdown or above the maximum recommended junction temperature reduces long-term reliability.

7.3.5 Current Limit

The device has an internal current limit circuit that protects the regulator during transient high-load current faults or shorting events. The current limit is a brickwall scheme. In a high-load current fault, the brickwall scheme limits the output current to the current limit (I_{CL}). I_{CL} is listed in the *Electrical Characteristics* table.

The output voltage is not regulated when the device is in current limit. When a current limit event occurs, the device begins to heat up because of the increase in power dissipation. When the device is in brickwall current limit, the pass transistor dissipates power $[(V_{IN} - V_{OUT}) \times I_{CL}]$. If thermal shutdown is triggered, the device turns off. After the device cools down, the internal thermal shutdown circuit turns the device back on. If the output current fault condition continues, the device cycles between current limit and thermal shutdown. For more information on current limits, see the *Know Your Limits* application report.

Figure 7-3 shows a diagram of the current limit.

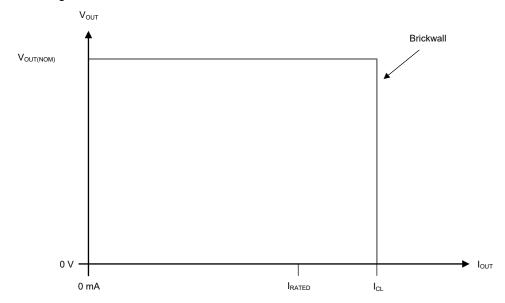


Figure 7-3. Current Limit

7.4 Device Functional Modes

7.4.1 Device Functional Mode Comparison

The *Device Functional Mode Comparison* table shows the conditions that lead to the different modes of operation. See the *Electrical Characteristics* table for parameter values.

Table 7-1. Device Functional Mode Comparison

| OPERATING MODE | PARAMETER | | | | |
|---|---|--|----------------------------|--|--|
| OPERATING MODE | V _{IN} | I _{OUT} | TJ | | |
| Normal operation | $V_{IN} > V_{OUT(nom)} + V_{DO}$ and $V_{IN} > V_{IN(min)}$ | I _{OUT} < I _{OUT(max)} | $T_J < T_{SD(shutdown)}$ | | |
| Dropout operation | $V_{IN(min)} < V_{IN} < V_{OUT(nom)} + V_{DO}$ | I _{OUT} < I _{OUT(max)} | $T_J < T_{SD(shutdown)}$ | | |
| Disabled (any true condition disables the device) | V _{IN} < V _{UVLO} | Not applicable | $T_{J} > T_{SD(shutdown)}$ | | |

7.4.2 Normal Operation

The device regulates to the nominal output voltage when the following conditions are met:

- The input voltage is greater than the nominal output voltage plus the dropout voltage (V_{OUT(nom)} + V_{DO})
- The output current is less than the current limit (I_{OLIT} < I_{CL})
- The device junction temperature is less than the thermal shutdown temperature (T_J < T_{SD})

7.4.3 Dropout Operation

If the input voltage is lower than the nominal output voltage plus the specified dropout voltage, but all other conditions are met for normal operation, the device operates in dropout mode. In this mode, the output voltage tracks the input voltage. During this mode, the transient performance of the device becomes significantly degraded because the pass transistor is in the ohmic or triode region, and acts as a switch. Line or load transients in dropout can result in large output-voltage deviations.

When the device is in a steady dropout state (defined as when the device is in dropout, $V_{IN} < V_{OUT(NOM)} + V_{DO}$, directly after being in a normal regulation state, but *not* during startup), the pass transistor is driven into the ohmic or triode region. When the input voltage returns to a value greater than or equal to the nominal output voltage plus the dropout voltage ($V_{OUT(NOM)} + V_{DO}$), the output voltage can overshoot for a short period of time while the device pulls the pass transistor back into the linear region.

7.4.4 Disabled

The output of the device can be shutdown by forcing the input voltage below the UVLO falling threshold (see the *Electrical Characteristics* table). When disabled, the pass transistor is turned off and internal circuits are shutdown.

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

8.1.1 Input and Output Capacitor Selection

The TPS7B87-Q1 requires an output capacitor of 2.2 μF or larger (1 μF or larger capacitance) for stability and an equivalent series resistance (ESR) between 0.001 Ω and 2 Ω . For best transient performance, use X5R- and X7R-type ceramic capacitors because these capacitors have minimal variation in value and ESR over temperature. When choosing a capacitor for a specific application, be mindful of the DC bias characteristics for the capacitor. Higher output voltages cause a significant derating of the capacitor. For best performance, the maximum recommended output capacitance is 220 μF .

Although an input capacitor is not required for stability, good analog design practice is to connect a capacitor from IN to GND. Some input supplies have a high impedance, thus placing the input capacitor on the input supply helps reduce the input impedance. This capacitor counteracts reactive input sources and improves transient response, input ripple, and PSRR. If the input supply has a high impedance over a large range of frequencies, several input capacitors can be used in parallel to lower the impedance over frequency. Use a higher-value capacitor if large, fast, rise-time load transients are anticipated, or if the device is located several inches from the input power source.

8.1.2 Dropout Voltage

Dropout voltage (V_{DO}) is defined as the input voltage minus the output voltage $(V_{IN} - V_{OUT})$ at the rated output current (I_{RATED}) , where the pass transistor is fully on. I_{RATED} is the maximum I_{OUT} listed in the *Recommended Operating Conditions* table. The pass transistor is in the ohmic or triode region of operation, and acts as a switch. The dropout voltage indirectly specifies a minimum input voltage greater than the nominal programmed output voltage at which the output voltage is expected to stay in regulation. If the input voltage falls to less than the nominal output regulation, then the output voltage falls as well.

For a CMOS regulator, the dropout voltage is determined by the drain-source on-state resistance ($R_{DS(ON)}$) of the pass transistor. Therefore, if the linear regulator operates at less than the rated current, the dropout voltage for that current scales accordingly. The following equation calculates the $R_{DS(ON)}$ of the device.

$$R_{\rm DS(ON)} = \frac{V_{\rm DO}}{I_{\rm RATED}} \tag{1}$$

8.1.3 Reverse Current

Excessive reverse current can damage this device. Reverse current flows through the intrinsic body diode of the pass transistor instead of the normal conducting channel. At high magnitudes, this current flow degrades the long-term reliability of the device.

Conditions where reverse current can occur are outlined in this section, all of which can exceed the absolute maximum rating of $V_{OUT} \le V_{IN} + 0.3 \text{ V}$.

- If the device has a large C_{OUT} and the input supply collapses with little or no load current
- The output is biased when the input supply is not established
- The output is biased above the input supply

If reverse current flow is expected in the application, external protection is recommended to protect the device. Reverse current is not limited in the device, so external limiting is required if extended reverse voltage operation is anticipated.

Submit Document Feedback

Copyright © 2021 Texas Instruments Incorporated

8.1.4 Power Dissipation (P_D)

Circuit reliability requires consideration of the device power dissipation, location of the circuit on the printed circuit board (PCB), and correct sizing of the thermal plane. The PCB area around the regulator must have few or no other heat-generating devices that cause added thermal stress.

To first-order approximation, power dissipation in the regulator depends on the input-to-output voltage difference and load conditions. The following equation calculates power dissipation (P_D).

$$P_{D} = (V_{IN} - V_{OUT}) \times I_{OUT}$$
 (2)

Note

Power dissipation can be minimized, and therefore greater efficiency can be achieved, by correct selection of the system voltage rails. For the lowest power dissipation use the minimum input voltage required for correct output regulation.

For devices with a thermal pad, the primary heat conduction path for the device package is through the thermal pad to the PCB. Solder the thermal pad to a copper pad area under the device. This pad area must contain an array of plated vias that conduct heat to additional copper planes for increased heat dissipation.

The maximum power dissipation determines the maximum allowable ambient temperature (T_A) for the device. According to the following equation, power dissipation and junction temperature are most often related by the junction-to-ambient thermal resistance ($R_{\theta JA}$) of the combined PCB and device package and the temperature of the ambient air (T_A).

$$T_{J} = T_{A} + (R_{\theta JA} \times P_{D}) \tag{3}$$

Thermal resistance $(R_{\theta JA})$ is highly dependent on the heat-spreading capability built into the particular PCB design, and therefore varies according to the total copper area, copper weight, and location of the planes. The junction-to-ambient thermal resistance listed in the *Thermal Information* table is determined by the JEDEC standard PCB and copper-spreading area, and is used as a relative measure of package thermal performance.

8.1.4.1 Thermal Performance Versus Copper Area

The most used thermal resistance parameter $R_{\theta JA}$ is highly dependent on the heat-spreading capability built into the particular PCB design, and therefore varies according to the total copper area, copper weight, and location of the planes. The $R_{\theta JA}$ recorded in the *Thermal Information* table in the *Specifications* section is determined by the JEDEC standard (see Figure 8-1), PCB, and copper-spreading area, and is only used as a relative measure of package thermal performance. For a well-designed thermal layout, $R_{\theta JA}$ is actually the sum of the package junction-to-case (bottom) thermal resistance ($R_{\theta JCbot}$) plus the thermal resistance contribution by the PCB copper.



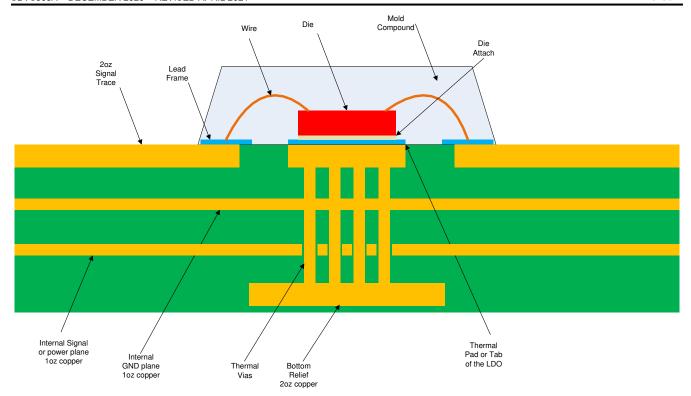
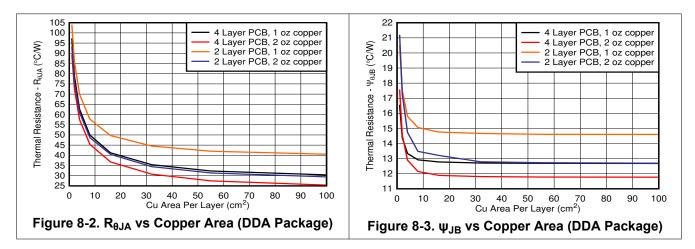
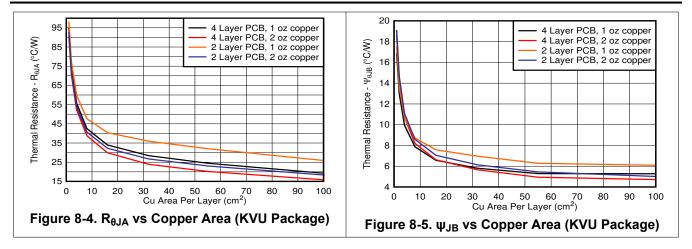


Figure 8-1. JEDEC Standard 2s2p PCB

Figure 8-2 through Figure 8-5 illustrate the functions of $R_{\theta JA}$ and ψ_{JB} versus copper area and thickness. These plots are generated with a 101.6-mm x 101.6-mm x 1.6-mm PCB of two and four layers. For the 4-layer board, inner planes use 1-oz copper thickness. Outer layers are simulated with both 1-oz and 2-oz copper thickness. A 2x3 (DDA package) or a 3x4 (KVU package) array of thermal vias with a 300- μ m drill diameter and 25- μ m copper plating is located beneath the thermal pad of the device. The thermal vias connect the top layer, the bottom layer and, in the case of the 4-layer board, the first inner GND plane. Each of the layers has a copper plane of equal area.





8.1.4.2 Power Dissipation Versus Ambient Temperature

Figure 8-6 is based off of a JESD51-7 4-layer, high-K board. The allowable power dissipation was estimated using the following equation. As discussed in the *An empirical analysis of the impact of board layout on LDO thermal performance* application report, thermal dissipation can be improved in the JEDEC high-K layout by adding top layer copper and increasing the number of thermal vias. If a good thermal layout is used, the allowable thermal dissipation can be improved by up to 50%.

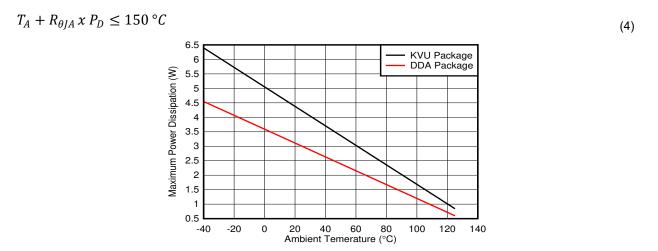


Figure 8-6. TPS7B87-Q1 Allowable Power Dissipation

8.1.5 Estimating Junction Temperature

The JEDEC standard now recommends the use of psi (Ψ) thermal metrics to estimate the junction temperatures of the linear regulator when in-circuit on a typical PCB board application. These metrics are not thermal resistance parameters and instead offer a practical and relative way to estimate junction temperature. These psi metrics are determined to be significantly independent of the copper area available for heat-spreading. The *Thermal Information* table lists the primary thermal metrics, which are the junction-to-top characterization parameter (ψ_{JT}) and junction-to-board characterization parameters provide two methods for calculating the junction temperature (T_{J}), as described in the following equations. Use the junction-to-top characterization parameter (ψ_{JT}) with the temperature at the center-top of device package (T_{T}) to calculate the junction temperature. Use the junction-to-board characterization parameter (ψ_{JB}) with the PCB surface temperature 1 mm from the device package (T_{B}) to calculate the junction temperature.

Copyright © 2021 Texas Instruments Incorporated

Submit Document Feedback



$$T_{I} = T_{T} + \psi_{IT} \times P_{D} \tag{5}$$

where:

- P_D is the dissipated power
- T_T is the temperature at the center-top of the device package

$$T_{J} = T_{B} + \psi_{JB} \times P_{D} \tag{6}$$

where

 T_B is the PCB surface temperature measured 1 mm from the device package and centered on the package edge

For detailed information on the thermal metrics and how to use them, see the *Semiconductor and IC Package Thermal Metrics* application report.

8.1.6 Pulling Up the PG Pin to a Different Voltage

Because the power-good (PG) pin is pulled up internally to the output rail, this pin cannot be pulled up to any voltage or wire AND'd like a typical open-drain PG output can be. If this signal must be pulled up to another logic level then an external circuit can be implemented using a PMOS transistor and a pullup resistor. Implementing the circuit shown in Figure 8-7 allows the outputs to be pulled up to any logic rail. If a PMOS transistor is used make sure to pick a transistor with a low threshold voltage as this will determine the output low voltage. this can also be done with a NMOS transistor, but it inverts the logic. This implementation also allows the outputs to be AND'd together like the traditional power-good pins.

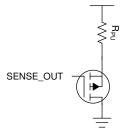


Figure 8-7. Additional Components for the PG Pin to be Pulled Up to Another Rail

Submit Document Feedback

Copyright © 2021 Texas Instruments Incorporated

8.1.7 Power-Good

8.1.7.1 Setting the Adjustable Power-Good Delay

The power-good delay time can be set in two ways: either by floating the DELAY pin or by connecting a capacitor from this pin to GND. When the DELAY pin is floating, the time defaults to $t_{(DLY_FIX)}$. The delay time is set by the following equation if a capacitor is connected between the DELAY pin and GND.

$$t = t_{(DLY_FIX)} + C_{DELAY} \left(\frac{V_{DLY(TH)}}{I_{DLY(CHARGE)}} \right)$$
(7)

8.2 Typical Application

Figure 8-8 shows a typical application circuit for the TPS7B87-Q1. TI recommends a low-ESR ceramic capacitor with a dielectric of type X5R or X7R.

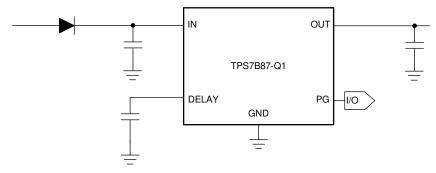


Figure 8-8. Typical Application Schematic for the TPS7B87-Q1

8.2.1 Design Requirements

For this design example, use the parameters listed in Table 8-1 as the input parameters.

 DESIGN PARAMETER
 EXAMPLE VALUE

 Input voltage range
 6 V to 40 V

 Output voltage
 5 V

 Output current
 350 mA

 Output capacitor
 10 μF

 Power-good delay capacitor
 100 nF

Table 8-1. Design Parameters

8.2.2 Detailed Design Procedure

8.2.2.1 Input Capacitor

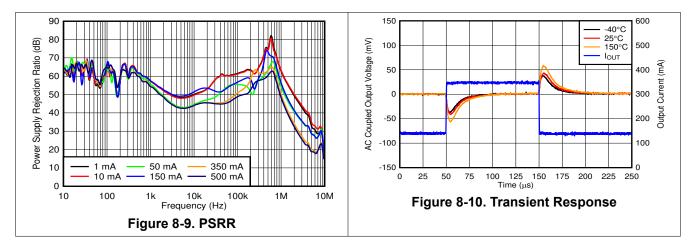
The device requires an input decoupling capacitor, the value of which depends on the application. The typical recommended value for the decoupling capacitor is 1 μ F. The voltage rating must be greater than the maximum input voltage.

8.2.2.2 Output Capacitor

The device requires an output capacitor to stabilize the output voltage. The capacitor value must be between 2.2 μF and 200 μF and the ESR range must be between 1 m Ω and 2 Ω . For this design, a low ESR, 10- μF ceramic capacitor was used to improve transient performance.



8.2.3 Application Curves



9 Power Supply Recommendations

This device is designed for operation from an input voltage supply with a range between 3 V and 40 V. This input supply must be well regulated. If the input supply is located more than a few inches from the TPS7B87-Q1, add an electrolytic capacitor with a value of 22 μ F and a ceramic bypass capacitor at the input.

10 Layout

10.1 Layout Guidelines

For best overall performance, place all circuit components on the same side of the circuit board and as near as practical to the respective LDO pin connections. Place ground return connections to the input and output capacitor, and to the LDO ground pin as close as possible to each other, connected by a wide, component-side, copper surface. The use of vias and long traces to the input and output capacitors is strongly discouraged and negatively affects system performance. TI also recommends a ground reference plane either embedded in the PCB itself or located on the bottom side of the PCB opposite the components. This reference plane serves to assure accuracy of the output voltage, shield noise, and behaves similarly to a thermal plane to spread (or sink) heat from the LDO device when connected to the thermal pad. In most applications, this ground plane is necessary to meet thermal requirements.

10.1.1 Package Mounting

Solder pad footprint recommendations for the TPS7B87-Q1 are available at the end of this document and at www.ti.com.

10.1.2 Board Layout Recommendations to Improve PSRR and Noise Performance

As depicted in Figure 10-1 and Figure 10-2, place the input and output capacitors close to the device for the layout of the TPS7B87-Q1. In order to enhance the thermal performance, place as many vias as possible around the device. These vias improve the heat transfer between the different GND planes in the PCB.

To improve AC performance such as PSRR, output noise, and transient response, TI recommends a board design with separate ground planes for V_{IN} and V_{OUT} , with each ground plane connected only at the GND pin of the device. In addition, the ground connection for the output capacitor must connect directly to the GND pin of the device.

Minimize equivalent series inductance (ESL) and ESR in order to maximize performance and ensure stability. Place each capacitor as close as possible to the device and on the same side of the PCB as the regulator itself.

Do not place any of the capacitors on the opposite side of the PCB from where the regulator is installed. TI strongly discourages the use of vias and long traces to connect the capacitors because may negatively affect system performance and even cause instability.

If possible, and to ensure the maximum performance specified in this document, use the same layout pattern used for the TPS7B87-Q1 evaluation board, available at www.ti.com.



10.2 Layout Examples

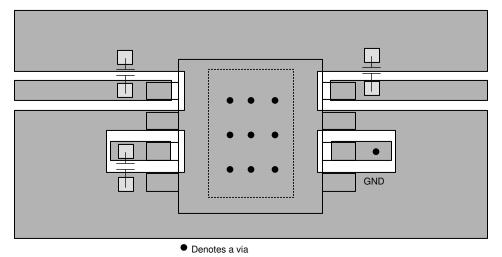
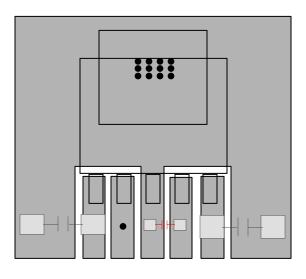


Figure 10-1. DDA Package Fixed Output



Denotes a via

Figure 10-2. KVU Package Fixed Outupt

11 Device and Documentation Support

11.1 Device Support

11.1.1 Device Nomenclature

Table 11-1. Device Nomenclature (1)

| PRODUCT | V _{OUT} | | | | | | | |
|------------------------------------|--|--|--|--|--|--|--|--|
| TPS7B87 xx Q yyy RQ1 | xx is the nominal output voltage (for example, 33 = 3.3 V V; 50 = 5.0 V). yyy is the package designator. Q indicates that this device is a grade-1 device in accordance with the AEC-Q100 standard. Q1 indicates that this device is an automotive grade (AEC-Q100) device. | | | | | | | |

(1) For the most current package and ordering information see the Package Option Addendum at the end of this document, or visit the device product folder on www.ti.com.

11.1.2 Development Support

For the PSpice model, see the TPS7B4250 PSpice Transient Model.

11.2 Documentation Support

11.2.1 Related Documentation

For related documentation see the following:

- Texas Instruments, Various Applications for Voltage-Tracking LDO application report
- Texas Instruments, TPS7B4250 Evaluation Module user's guide
- Texas Instruments, TPS7B5250-Q1 Pin FMEA application report

11.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

11.4 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

11.5 Trademarks

TI E2E[™] is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

11.6 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

11.7 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

www.ti.com 29-Jul-2021

PACKAGING INFORMATION

| Orderable Device | Status (1) | Package Type | Package Drawing | Pins | Package Qty | Eco Plan | Lead finish/ Ball material | MSL Peak Temp | Op Temp (°C) | Device Marking (4/5) | Samples |
|--------------------|------------|--------------|--------------------|------|----------------|--------------|-------------------------------|---------------------|--------------|-------------------------|---------|
| TPS7B8733QDDARQ1 | ACTIVE | SO PowerPAD | DDA | 8 | 2500 | RoHS & Green | NIPDAUAG | Level-2-260C-1 YEAR | -40 to 150 | 7B8733 | Samples |
| TPS7B8733QKVURQ1 | ACTIVE | TO-252 | KVU | 5 | 2500 | RoHS & Green | SN | Level-3-260C-168 HR | -40 to 150 | 7B8733 | Samples |
| TPS7B8733QKVURQ1R2 | ACTIVE | TO-252 | KVU | 5 | 2500 | RoHS & Green | SN | Level-3-260C-168 HR | -40 to 150 | 7B8733 | Samples |
| TPS7B8750QDDARQ1 | ACTIVE | SO PowerPAD | DDA | 8 | 2500 | RoHS & Green | NIPDAUAG | Level-2-260C-1 YEAR | -40 to 150 | 7B8750 | Samples |
| TPS7B8750QKVURQ1 | ACTIVE | TO-252 | KVU | 5 | 2500 | RoHS & Green | SN | Level-3-260C-168 HR | -40 to 150 | 7B8750 | Samples |
| TPS7B8750QKVURQ1R2 | ACTIVE | TO-252 | KVU | 5 | 2500 | RoHS & Green | SN | Level-3-260C-168 HR | -40 to 150 | 7B8750 | Samples |

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.



PACKAGE OPTION ADDENDUM

www.ti.com 29-Jul-2021

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

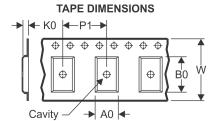
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

www.ti.com 30-Jul-2021

TAPE AND REEL INFORMATION





| | Dimension designed to accommodate the component width |
|----|---|
| | Dimension designed to accommodate the component length |
| K0 | Dimension designed to accommodate the component thickness |
| W | Overall width of the carrier tape |
| P1 | Pitch between successive cavity centers |

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

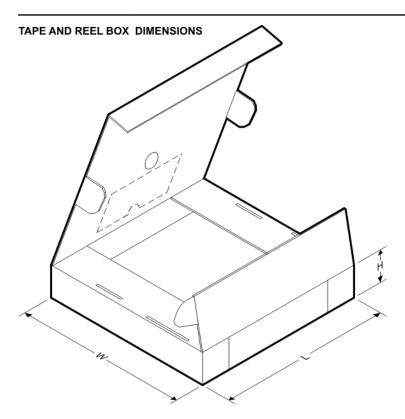


*All dimensions are nominal

| Device | Package Type | Package Drawing | | SPQ | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|--------------------|--------------------|--------------------|---|------|--------------------------|--------------------------|------------|------------|------------|------------|-----------|------------------|
| TPS7B8733QDDARQ1 | SO Power PAD | DDA | 8 | 2500 | 330.0 | 12.8 | 6.4 | 5.2 | 2.1 | 8.0 | 12.0 | Q1 |
| TPS7B8733QKVURQ1R2 | TO-252 | KVU | 5 | 2500 | 330.0 | 16.4 | 6.9 | 10.5 | 2.7 | 8.0 | 16.0 | Q2 |
| TPS7B8750QDDARQ1 | SO Power PAD | DDA | 8 | 2500 | 330.0 | 12.8 | 6.4 | 5.2 | 2.1 | 8.0 | 12.0 | Q1 |
| TPS7B8750QKVURQ1R2 | TO-252 | KVU | 5 | 2500 | 330.0 | 16.4 | 6.9 | 10.5 | 2.7 | 8.0 | 16.0 | Q2 |

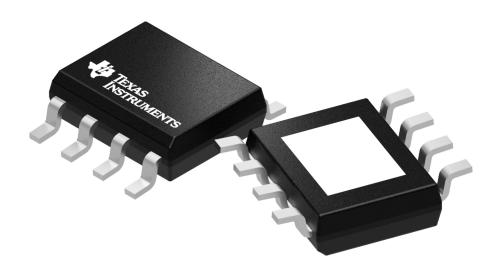
PACKAGE MATERIALS INFORMATION

www.ti.com 30-Jul-2021



*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
|--------------------|--------------|-----------------|------|------|-------------|------------|-------------|
| TPS7B8733QDDARQ1 | SO PowerPAD | DDA | 8 | 2500 | 366.0 | 364.0 | 50.0 |
| TPS7B8733QKVURQ1R2 | TO-252 | KVU | 5 | 2500 | 340.0 | 340.0 | 38.0 |
| TPS7B8750QDDARQ1 | SO PowerPAD | DDA | 8 | 2500 | 366.0 | 364.0 | 50.0 |
| TPS7B8750QKVURQ1R2 | TO-252 | KVU | 5 | 2500 | 340.0 | 340.0 | 38.0 |



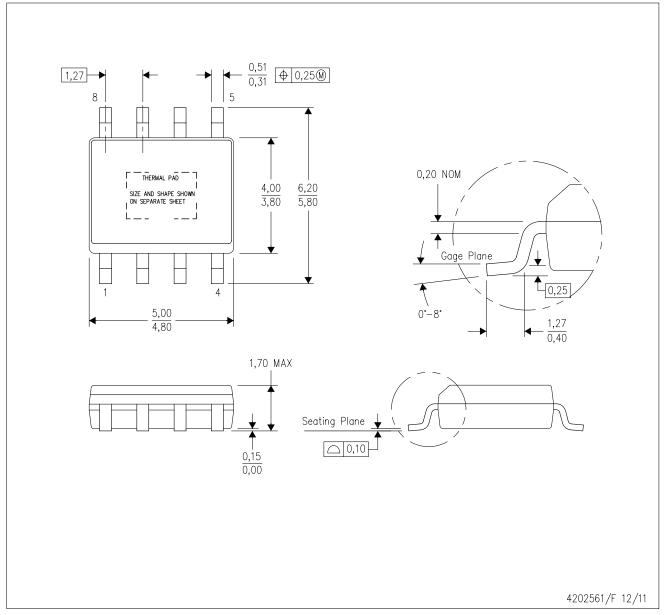
Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4202561/G



DDA (R-PDSO-G8)

PowerPAD ™ PLASTIC SMALL-OUTLINE



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 for information regarding recommended board layout. This document is available at www.ti.com http://www.ti.com.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
- F. This package complies to JEDEC MS-012 variation BA

PowerPAD is a trademark of Texas Instruments.



DDA (R-PDSO-G8)

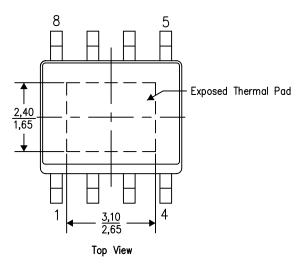
PowerPAD™ PLASTIC SMALL OUTLINE

THERMAL INFORMATION

This PowerPAD package incorporates an exposed thermal pad that is designed to be attached to a printed circuit board (PCB). The thermal pad must be soldered directly to the PCB. After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For additional information on the PowerPAD package and how to take advantage of its heat dissipating abilities, refer to Technical Brief, PowerPAD Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 and Application Brief, PowerPAD Made Easy, Texas Instruments Literature No. SLMA004. Both documents are available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Exposed Thermal Pad Dimensions

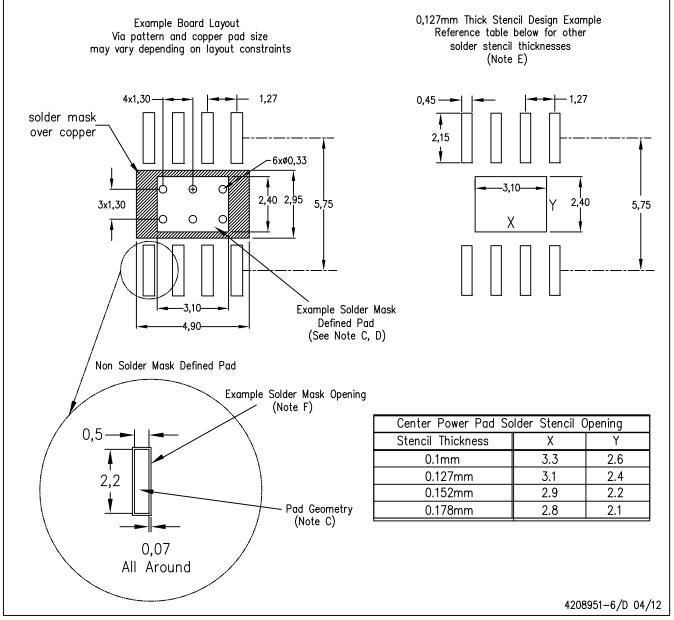
4206322-6/L 05/12

NOTE: A. All linear dimensions are in millimeters



DDA (R-PDSO-G8)

PowerPAD™ PLASTIC SMALL OUTLINE

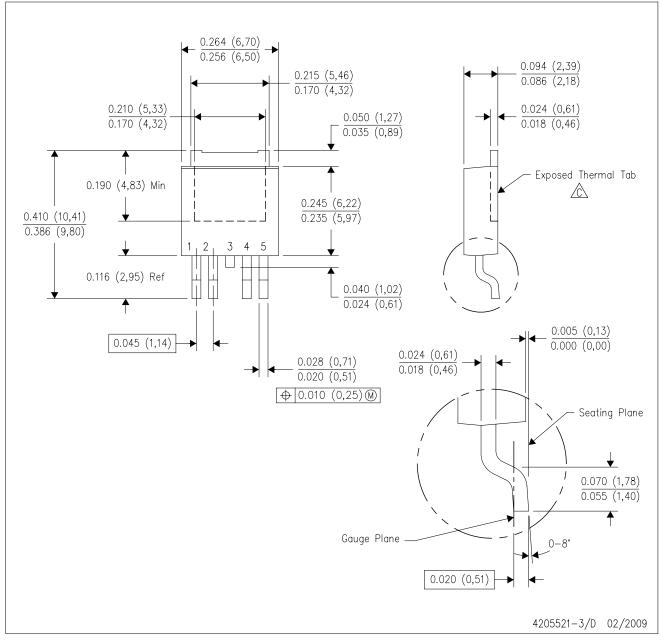


NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad Thermally Enhanced Package, Texas Instruments Literature No. SLMA002, SLMA004, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com http://www.ti.com. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.
- F. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

PowerPAD is a trademark of Texas Instruments.





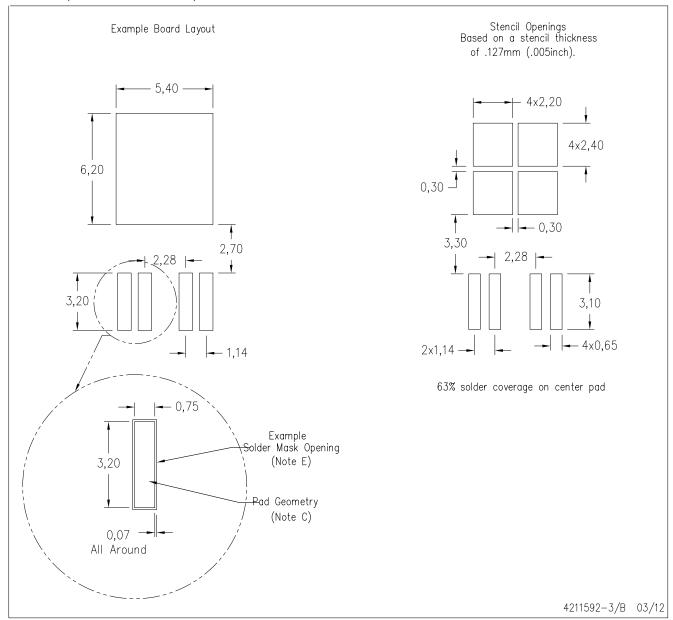
NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- The center lead is in electrical contact with the exposed thermal tab.
- D. Body Dimensions do not include mold flash or protrusions. Mold flash and protrusion shall not exceed 0.006 (0,15) per side.
- E. Falls within JEDEC TO-252 variation AD.



KVU (R-PSFM-G5)

PLASTIC FLANGE MOUNT PACKAGE



NOTES:

- A. All linear dimensions are in millimeters.
- 3. This drawing is subject to change without notice.
- C. Publication IPC-SM-782 is an alternate information source for PCB land pattern designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in thermal pad.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, or other requirements. These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale (https://www.ti.com/legal/termsofsale.html) or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2021, Texas Instruments Incorporated